

Supplementary Information

for paper “Single-bilayer graphene test structures for Kelvin probe microscopy”

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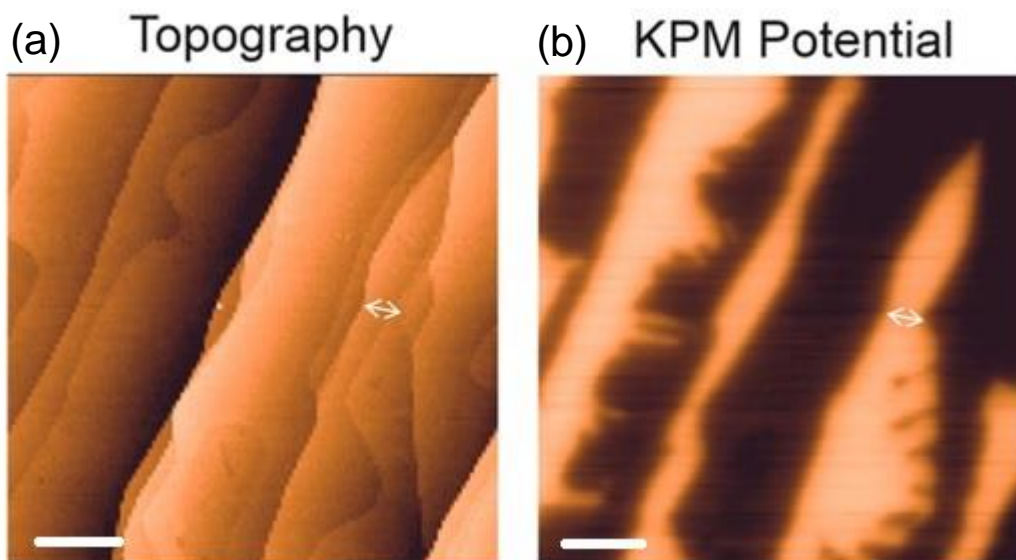


Figure S1. Images of test sample after deconvolution procedure (a) - topography and (b) – corresponding KPM potential. Scale bar is 500nm.

It should be noted, that there is no capacitance related correlation effect between obtained SPM topography and KPM potential distribution map. Figure S1 is an example of a pair of images “topography + KPM potential” obtained in the two-pass mode. Our procedure for extracting the PSF and further deconvolution of the KPM potential affected only the potential data, the topography data were not perturbed. It is possible to measure the distances between characteristic points (step corners) on the topography image and on the KPM (arrows in the figure below). These distances are the same, there are no perturbations of the lengths.